

CWS ASUR-SDR™ Training

This course involves a careful introduction to ASUR-SDR in an intensive three-day training sessions held at the customer's site. Either one of those training courses assumes the customer has, or will purchase, any of the core solutions from Core Wafer: SDR, PDR, RDA, PDQ-WLR or PDQ-Fab test structures.

Basic physics, basic probability and statistics theory, test methodologies, test design, software training, data analysis and interpretation are covered for each of the major failure mechanisms studied. The class provides a training manual that covers all topics discussed

Syllabus

Day One:

- Introduction
- Basic Semiconductor Physics
- Reliability Concepts
- Probability and Statistics
- Reliability Test Systems
- Testing Concepts and Components
- Metal Reliability (EM)
- Charge Pumping
- Hot Carrier Induced Degradation
- Bias Temperature Stress
- Plasma Damage
- Oxide Integrity Tests
- Mobile Ions Characterization
- Q&A

Day Two:

- Introduction to ASUR-SDR
- Software Configuration
- Testplan Builder (HCI+BTI builders)
- Algorithm Builder – C/Basic
- IMT Tool
- Algorithm Mode
- Testplan Mode Execution

Day Three:

- Hands-on training
- Set-up sample testplan
- Test Execution
- Data Analysis
- Q&A

